

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/717,464	SAINT ETIENNE ET AL.	
Examiner	Art Unit	
Feben M. Haile	2616	

SEARCHED					
Class	Subclass	Date	Examiner		
370	235	4/26/2007	FH		
370	217	4/26/2007	FH		
370	223	4/26/2007	FH		
370	278	4/26/2007	FH		
370	392	4/26/2007	FH		
370	252	4/26/2007	FH		
370	399	4/26/2007	FH		
370	394	4/26/2007	FH		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u> </u>				

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Search: duplex, Ethernet, switch, router, virtual, logical, sequence, passband, packet, gap, time, CRC	4/26/2007	FH
		,